

PCN# 20121106004
Qualification of TI Clark as Additional Assembly/Test Site
for Select RHU Package Devices in the TQFN Family
Change Notification / Sample Request

Date: 11/14/2012
To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

Sincerely,

PCN Team
SC Business Services
Phone: +1(214) 480-6037
Fax: +1(214) 480-6659

20121106004
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TS3DV520ERHUR	null
TS3L500AERHUR	null

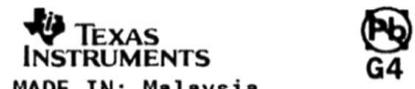
Technical details of this Product Change follow on the next page(s).

PCN Number:	20121106004	PCN Date:	11/14/2012												
Title:	Qualification of TI Clark as Additional Assembly/Test Site for Select RHU Package Devices in the TQFN Family														
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037												
Dept:	Quality Services														
Proposed 1st Ship Date:	02/14/2013	Estimated Sample Availability:	Date Provided at Sample request												
Change Type:															
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process												
<input checked="" type="checkbox"/>	Design	<input type="checkbox"/>	Assembly Materials												
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Electrical Specification												
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Mechanical Specification												
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Test Process												
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Bump Material												
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Bump Process												
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Materials												
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process												
PCN Details															
Description of Change:															
<p>Qualification of TI Clark as Additional Assembly/Test Site for Select devices in the RHU Package of the TQFN Family. Additionally, conversion from Au Wire to Cu Wire and mount and mold compound changes. Assembly differences are shown in the following table:</p> <table border="1"> <thead> <tr> <th></th> <th>NSE</th> <th>TI Clark</th> </tr> </thead> <tbody> <tr> <td>Mount Compound</td> <td>PZ0031</td> <td>4207123</td> </tr> <tr> <td>Mold Compound</td> <td>CZ0134</td> <td>4208625</td> </tr> <tr> <td>Wire</td> <td>1.30 Mil Au</td> <td>0.96 Mil Cu</td> </tr> </tbody> </table> <p>Qualification testing will be performed at both MSL1 and MSL2 conditions and the Clark assembled devices will be released at the highest level passing MSL. The devices in the product affected list are being qualified by similarity (see Qualification Data). Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.</p>					NSE	TI Clark	Mount Compound	PZ0031	4207123	Mold Compound	CZ0134	4208625	Wire	1.30 Mil Au	0.96 Mil Cu
	NSE	TI Clark													
Mount Compound	PZ0031	4207123													
Mold Compound	CZ0134	4208625													
Wire	1.30 Mil Au	0.96 Mil Cu													
Reason for Change:															
<p>Continuity of supply.</p> <ol style="list-style-type: none"> 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock 															
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):															
No impact on form, fit, function, quality or reliability.															

Changes to product identification resulting from this PCN:

Assembly Site		
NSE Thailand	Assembly Site Origin (22L)	ASO: NSE
TI Clark Philippines	Assembly Site Origin (22L)	ASO: QAB

Sample product shipping label (not actual product label)




(1P) SN74LS07NSR
 (Q) 2000 (D) 0336
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: (V) 0033317
 (20L) ~~CSO: SHE~~ (21L) CCO:USA
 (22L) ASO: MLA (23L) ACO: MYS

MADE IN: Malaysia
 2DC: 20:
 MSL '2 /260C/1 YEAR SEAL DT
 MSL 1 /235C/UNLIM 03/29/04
 OPT:
 ITEM: 39
 LBL: 5A (L)TO:1750

Assembly site Codes: NSE = J, TI-Clark = I

Product Affected:

TS3DV520ERHUR	TS3L500AERHUR
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Qualification Plan

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qualification Schedule:	Start:	December 2012	End:	March 2013
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Qual Vehicle 1: TS3DV520ERHUR (MSL1-260C)

Package Construction Details

Assembly Site:	Clark-AT	Mold Compound:	4208625
# Pins-Designator, Family:	56-RHU, TQFN	Mount Compound:	4207123
Lead Finish, Base	NiPdAuAg, Cu	Bond Wire:	0.96 Mil Diameter Cu

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size / Fail		
		Lot 1	Lot 2	Lot 3
Ball Bond Shear	76 balls, 3 units minimum	76/0	76/0	76/0
Bond Pull	76 wire, 3 units minimum	76/0	76/0	76/0
Manufacturability (Assembly)	(per mfg. Site specification)	1/0	1/0	1/0
X-ray	(top side only)	5/0	5/0	5/0

Qual Vehicle 2: TS3L500AERHUR (MSL1-260C)

Package Construction Details

Assembly Site:	Clark-AT	Mold Compound:	4208625
# Pins-Designator, Family:	56-RHU, TQFN	Mount Compound:	4207123
Lead Finish, Base	NiPdAuAg, Cu	Bond Wire:	0.96 Mil Diameter Cu

Qualification: <input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results				
Reliability Test	Conditions	Sample Size / Fail		
		Lot 1	Lot 2	Lot 3
**High Temp. Storage Bake	170C (420hrs, 600hrs)	77/0	77/0	77/0
**Autoclave	121C, 2 ATM (96 Hrs)	78/0	78/0	78/0
**Temperature Cycle	50-65C/150C, (500 Cycles)	77/0	77/0	77/0
Ball Bond Shear	76 balls, 3 units minimum	76/0	76/0	76/0
Bond Pull	76 wire, 3 units minimum	76/0	76/0	76/0
Manufacturability (Assembly)	(per mfg. Site specification)	1/0	1/0	1/0
Manufacturability Qualification (MQ)	(per mfg. Site specification)	1/0	-	-
X-ray	(top side only)	5/0	5/0	5/0

** Preconditioning sequence: Level 1-260C.

Reference Qualification for Cu Wire at TI-Clark

Qualification Data: Approved 07/01/2011				
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.				
Qual Vehicle 1 : SN75DP122ARTQ (MSL3-260C)				
Package Construction Details				
Assembly Site:	TI Clark	Mold Compound:	4208625	
# Pins-Designator, Family:	56-RTQ, VQFN	Mount Compound:	4207768	
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 Mil Dia., Cu	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results				
Reliability Test	Conditions	Sample Size / Fail		
		Lot 1	Lot 2	Lot 3
**High Temperature Storage Bake	170C (420 Hours)	77/0	77/0	77/0
**Autoclave	121C, 2 ATM (96 Hours)	77/0	77/0	77/0
**Temperature Cycle	-65C/+150C, (500 Cycles)	77/0	77/0	77/0
Ball Bond Shear	76 balls, 3 units minimum	76/0	76/0	76/0
Bond Pull	76 wire, 3 units minimum	76/0	76/0	76/0
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass
X-ray	(top side only)	5/0	5/0	5/0

** - Preconditioning sequence: Level 3-260C.

Qualification Data: Approved 12/01/2010				
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.				
Qual Vehicle 1 : TPS51216 (MSL2-260C)				
Package Construction Details				
Assembly Site:	TI Malaysia	Mold Compound:	4208625	
# Pins-Designator, Family:	20-RUK, QFN	Mount Compound:	4207768	
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 Mil Dia., Cu	

Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results				
Reliability Test	Conditions	Sample Size / Fail		
		Lot 1	Lot 2	Lot 3
**Steady-state Life Test	150C (168, 300 Hrs)	77/0	77/0	77/0
Electrical Char.	Per Device specification	passed	--	--
**High Temperature Storage Bake	170C (420 Hours)	77/0	77/0	77/0
**Biased HAST	130C/85%RH (96 Hrs)	77/0	77/0	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0
ESD HBM	500V, 1000V, 1500V, 2000V	3/0	3/0	3/0
ESD CDM	200V, 500V	3/0	3/0	3/0
Latch-up	(per JESD78)	6/0	6/0	6/0
Manufacturability/ TQ/MQ	(per mfg. Site specification)	passed	passed	passed
Pre/Post Temp Cycle SAM	CSAM and TSAM analysis	passed	passed	passed
**- Preconditioning sequence: Level 2-260C.				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com